

Performance characteristics

Frequency range: 4 - 20 GHz Small Signal Gain: 25 dB Gain flatness: ± 0.75dB Noise figure: 3.8dB typ.

P-1dB: 21 dBm Psat: 22dBm

Power supply: +5V/ 150mA

500hm input/output 100% on-chip testing

Chip size: 1.96 x 1.22 x 0.1mm

Product Introduction

GPA-0420E is a broadband amplifier chip based on GaAs technology, with a frequency range of 4~20GHz, a small signal gain of 25dB, and a saturated output power of 22dBm. The chip is powered by a single +5V power supply and supports +3.5V, +4V, and +6V operation. The chip through-hole metallization process ensures good grounding, and the back side is metallized, which is suitable for eutectic sintering or conductive adhesive bonding process.

Use restriction parameter ¹		
Maximum drain voltage	+8 V	
Maximum input power	+20dBm	
Operating temperature	-55 ~ + 85 °C	
Storage temperature	-65 ~ +150°C	

[1] Exceeding any of these maximum limits may cause permanent damage.

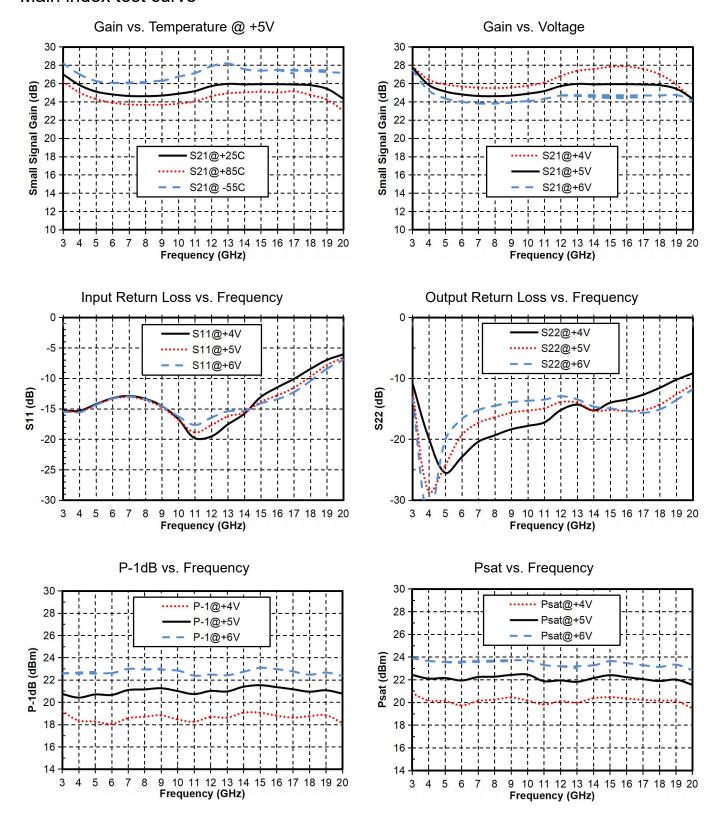
Electrical performance parameters (TA = $+25^{\circ}$ C , Vd = $+5V$)				
Index	Minimum	Typical Value	Maximum	Unit
Frequency Range		4-20		GHz
Small Signal Gain	24	25	25.5	dB
Gain Flatness		± 0.75		dB
Noise Figure		3.8		dB
Reverse Isolation		64		dB
P -1 dB		21		dBm
Psat		22		dBm
Input return loss	6	13		dB
Output return loss	11	16		dB
Quiescent Current		150		mA

Add: 101 cecil street #14-10, tong eng building singapore 069533 Email: info@standardcircuit.com

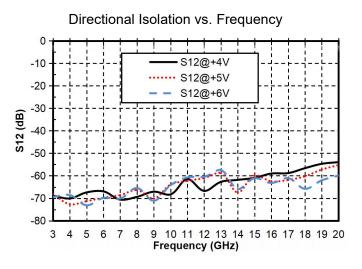
Web: www.standardcircuit.com Tel: +65 82613258

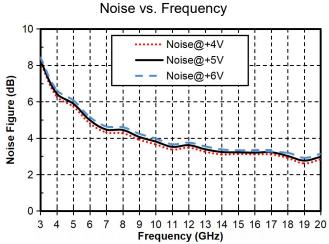


Main index test curve

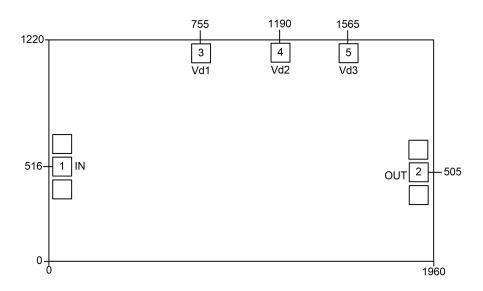








Appearance structure ²

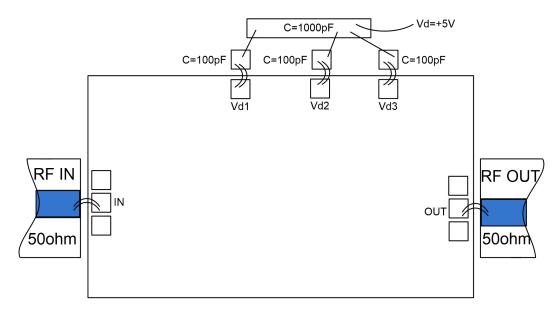


[2] All units in the figure are micrometers

Bonding point definition			
Bonding point	Function	Functional Description	
number	Symbol		
1	RF IN	RF signal input terminal, no DC blocking capacitor required.	
2	RF OUT	RF signal output terminal, no DC blocking capacitor required.	
3, 4, 5	Vd	Amplifier drain bias, external 100pF , 1000pF bypass capacitor required.	
Chip bottom	GND	The bottom of the chip needs to be in good contact with the RF and DC	
		grounds.	



Recommended assembly diagram



Notice

- The chip must be stored in an anti-static container and kept in a nitrogen environment.
- Do not attempt to clean the bare die surface using wet chemical methods.
- Please strictly follow the ESD protection requirements to avoid static damage to the bare chip.
- General operation: Please use precision pointed tweezers to pick up bare chips. Avoid touching the chip surface with tools or fingers during operation.
- Rack mounting operation suggestions: Bare chip mounting can be done by AuSn solder eutectic sintering
 or conductive adhesive bonding. The mounting surface must be clean and flat.
- Sintering process: It is recommended to use AuSn solder sheets with a gold-tin ratio of 80/20. The working surface temperature reaches 255 °C and the tool (vacuum chuck) temperature reaches 265 °C. When the high-temperature mixed gas (nitrogen-hydrogen ratio of 90/10) is blown to the chip, the temperature at the top of the tool should be raised to 290 °C. Do not let the chip exceed 320 °C for more than 20 seconds. The friction time should not exceed 3 seconds.
- Bonding process: The amount of conductive glue dispensed should be as small as possible. After the chip
 is placed in the installation position, the conductive glue can be vaguely seen around it. For curing
 conditions, please follow the information provided by the conductive glue manufacturer.
- Bonding operation suggestions: Use Φ0.025mm (1mil) gold wire for both ball and wedge bonding. Thermosonic bonding temperature is 150 °C. The pressure of the wedge bonding knife is 40~50gf for ball bonding and 18~22gf for wedge bonding. Use the smallest possible ultrasonic energy. The bonding starts at the pressure point on the chip and ends at the package (or substrate).